



PATENT
Customer No. 22,852
Attorney Docket No. 04329.2509

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)
)
Kazuya Sato et al.) Group Art Unit: 2877
)
Application No.: 09/783,295) Examiner: to be assigned
)
Filed: February 15, 2001)
)
For: METHOD FOR INSPECTING)
EXPOSURE APPARATUS)

Commissioner for Patents
Washington, DC 20231

Sir:

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT UNDER
37 C.F.R. § 1.97(b)

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(b), applicant brings to the attention of the Examiner the documents listed on the attached PTO 1449. This Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits for the above-referenced application.

Copies of the listed documents, including any copending patent applications, are attached. Further Japanese KOKAI Pub. No. 2000-21732 was previously submitted in an Information Disclosure Statement on February 15, 2001.

The following is a supplemental concise statement of relevance of the non-English language document.

Japanese KOKAI Pub. No. 2000-21732 discloses a method of inspecting an exposure apparatus, the exposure apparatus comprising an illumination optical system

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1 that guides light emitted from a light source to a reticle 2, and a projection optical system 3 that transfers a reduced projection image of the reticle 2 onto a wafer 5, the method inspecting a form of the light source of the exposure apparatus, a form of pupil 4 of the projection optical system 3, and a concentricity between the light source form and the form of the pupil 4, wherein the reticle 2 includes a grating pattern in which a light transmission part and opaque part are repeated at finite periods, a light is irradiated onto the reticle 2, and a primary diffraction light that has passed through the reticle 2 is irradiated onto an outer edge of the pupil 4 of the projection optical system 3, and a pattern image of the reticle 2 is formed by exposure on a wafer 5 in a defocused state.

Additionally, Japanese KOKAI Publication No. 2000-21732 corresponds to U.S. Patent No, 6,317,198 also being submitted herewith.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that each or all of the listed documents are material or constitute "prior art." If the Examiner applies any of the documents as prior art against any claim in the application and Applicants determine that the cited document do not constitute "prior art" under United States law, Applicants reserves the right to present to the office the relevant facts and law regarding the appropriate status of such documents.

Applicants further reserves the right to take appropriate action to establish the patentability of the disclosed invention over the listed documents, should one or more of the documents be applied against the claims of the present application.

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If there is any fee due in connection with the filing of this Statement, please
charge the fee to our Deposit Account No. 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW,
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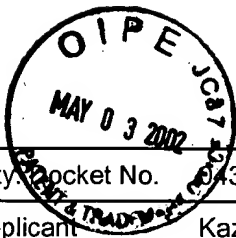
Dated: May 3, 2002

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INFORMATION DISCLOSURE CITATION

Atty. Pocket No.	4329.2509	Appln. No.	09/783,295
Applicant	Kazuya Sato et al.		
Filing Date	February 15, 2001	Group:	2877

U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
	US 6,317,198	Nov. 13, 2001	Sato et al.			

FOREIGN PATENT DOCUMENTS

Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No
Japanese KOKAI Pub. No. 2000-21732					Abstract

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner	Date Considered
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	
Form PTO 1449	Patent and Trademark Office - U.S. Department of Commerce